

Search Notes



Application/Control No.

10/605,726

Examiner

Stephen W. Smoot

Applicant(s)/Patent under Reexamination

ZHU ET AL.

Art Unit

2813

SEARCHED

Class	Subclass	Date	Examiner
438	151	2/5/2005	SWS
438	270	2/5/2005	SWS
438	295	2/5/2005	SWS
438	300	2/5/2005	SWS
438	589	2/5/2005	SWS
438	595	2/5/2005	SWS
257	347	2/5/2005	SWS
257	387	2/5/2005	SWS

S.W.S.

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
Key Words: SOI - BOX, SiGe, Silicon Epitaxial Layer;	2/5/2005	<i>S.W.S.</i> SWS
Elevated Source/Drain - Raised; Recessed Gate - Trench, Groove, Damascene, Inlaid.	2/5/2005	<i>S.W.S.</i> SWS
Search Tools - EAST (attached): USPAT; US PG PUBS; Derwent; EPO; JPO; IBM TDB	2/5/2005	<i>S.W.S.</i> SWS